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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
10/642,808	08/15/2003	Chunsheng Huang	NAN065 US	3123
34036 7:	590 08/24/2005		EXAM	INER
SILICON VALLEY PATENT GROUP LLP			NGUYEN, TU T	
2350 MISSION COLLEGE BOULEVARD SUITE 360 SANTA CLARA, CA 95054			ART UNIT	PAPER NUMBER
			2877	
	,			

DATE MAILED: 08/24/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

		AV
	Application No.	Applicant(s)
	10/642,808	HUANG, CHUNSHENG
Office Action Summary	Examiner	Art Unit
	Tu T. Nguyen	2877
The MAILING DATE of this communication appeariod for Reply	opears on the cover sheet w	vith the correspondence address
A SHORTENED STATUTORY PERIOD FOR REPI THE MAILING DATE OF THIS COMMUNICATION - Extensions of time may be available under the provisions of 37 CFR 1. after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reg If NO period for reply is specified above, the maximum statutory period Failure to reply within the set or extended period for reply will, by statu Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	.136(a). In no event, however, may a ply within the statutory minimum of thi d will apply and will expire SIX (6) MO tte, cause the application to become A	reply be timely filed rty (30) days will be considered timely. NTHS from the mailing date of this communication. BANDONED (35 U.S.C. § 133).
Status		
1) Responsive to communication(s) filed on	<u></u> .	
2a) This action is FINAL . 2b) ⊠ Th	is action is non-final.	
3) Since this application is in condition for allow:	·	·
closed in accordance with the practice under	Ex parte Quayle, 1935 C.I	D. 11, 453 O.G. 213.
Disposition of Claims	•	
4) Claim(s) 1-18 is/are pending in the application	n.	•
4a) Of the above claim(s) is/are withdra	awn from consideration.	
5)⊠ Claim(s) <u>1-6</u> is/are allowed.		
6)⊠ Claim(s) <u>7 and 13-18</u> is/are rejected.		
7)⊠ Claim(s) <u>8-12</u> is/are objected to.		
8) Claim(s) are subject to restriction and/	or election requirement.	
Application Papers		
9)☐ The specification is objected to by the Examin	ner.	
10)⊠ The drawing(s) filed on <u>15 August 2003</u> is/are	e: a)⊠ accepted or b)⊡ o	bjected to by the Examiner.
Applicant may not request that any objection to the	• • • • • • • • • • • • • • • • • • • •	
Replacement drawing sheet(s) including the corre	·	
11) The oath or declaration is objected to by the E	Examiner. Note the attache	d Office Action or form PTO-152.
Priority under 35 U.S.C. § 119		
12) Acknowledgment is made of a claim for foreiga) All b) Some * c) None of:	n priority under 35 U.S.C.	§ 119(a)-(d) or (f).
1. Certified copies of the priority documer	nts have been received.	
2. Certified copies of the priority documer	nts have been received in A	Application No
Copies of the certified copies of the pri	ority documents have been	received in this National Stage
application from the International Burea	au (PCT Rule 17.2(a)).	
* See the attached detailed Office action for a lis	st of the certified copies no	t received.
Attachment(s)		
1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948)		Summary (PTO-413) (s)/Mail Date.

U.S. Patent and Trademark Office PTOL-326 (Rev. 1-04)

3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date <u>08/15/2003</u>.

6) Other: _

5) Notice of Informal Patent Application (PTO-152)

DETAILED ACTION

Claim Objections

Claim 15 is objected to because of the following informalities:

- 1) Claim 15, line 3, "an initial measurement" should be changed to "the initial measurement".
- 2) Claim 15, line 3, "a first reference location" should be changed to "the first reference location".
 - 3) Claim 15, line 3, "a second" should be changed to "the second".
- 4) Claim 15, line 8, "a subsequent measurement" should be changed to "the subsequent measurement".

Claim Rejections - 35 USC § 112

The following is a quotation of the second paragraph of 35 U.S.C. 112:

The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.

Claims 13-18 are rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention.

Claim 13, line 9, the phrase "after the sample" is not ambiguous. The location of the phase retarder is not clear. What does applicant mean "after the sample"?

Claims 14-18 are also rejected as being depended on a rejected claim.

Claim Rejections - 35 USC § 103

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The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claim 7 is rejected under 35 U.S.C. 103(a) as being unpatentable over Carter et al (5,771,094).

With respect to claim 7, Carter discloses method for correcting calibration function of an ellipsometer. The method comprises: producing an initial measurement of at least one reference location STEP1, STEP2 (fig 2) using an ellipsometer (fig 1); producing a subsequent measurement of the at least one reference location STEP3 (fig 2) with the ellipsometer (fig 1); using the initial measurement of the least one reference location with the subsequent measurement of the least one reference location to correct the calibration of the ellipsometer STEP4-STEP8 (fig 2) (column 2, lines 13-30 and column 4, lines 40-66).

Carter does not explicitly disclose determining the calibration error as claimed.

However, by disclosing correcting the calibration of the ellipsometer, it would have been obvious that Carter would have to have the claimed step of determining the calibration error before correcting the calibration.

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Claims 13-14,16-18 are rejected under 35 U.S.C. 103(a) as being unpatentable over Carter et al (5,771,094) in view of Lee at al (6,184,984).

With respect to claim 13, refer to discussion in claim 7 above for the computer system. Carter does not explicitly disclose the claimed ellipsometer. Lee discloses an ellipsometer. The ellipsometer comprises: a polarization state generator, including an electromagnetic source 10 and 88 (fig 1), the polarization state generator produces an electromagnetic beam of known polarization state that is incident on the at least one reference location during calibration (abstract or teaching using the claimed polarization state generator in column 1, lines 25-30); a phase retarder in the path of the electromagnetic beam after the sample (column 16, lines 4-10); at least one detector that receives the electromagnetic beam after is incident on the at least one reference location 72 and 74 (fig 1). It would have been obvious to use Cater's computer to determining the calibration error of Lee's ellipsometter to facilitate the measuring.

With respect to claim 14, It would have been obvious to modify Carter to measure at different locations as claimed to facilitate the measurement. Further Carter discloses using a movement X-Y sample stage (column 6, lines 7-15). It would have been obvious that Carter's system could measure any desired reference locations.

With respect to claims 16-17, it would have been obvious a design choice to modify Carter's first and second reference locations as claimed for different system set up. The modification involves only routine skill in the art.

With respect to claim 18, it would have been obvious to modify Carter to put the sample in a vacuum or inert gas or an ambient environment to facilitate the measuring.

Allowable Subject Matter

Claims 1-6 are allowed.

Claims 8-12, 15 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

The following is a statement of reasons for the indication of allowable subject matter: Prior arts of record do not disclose a method. The method comprises: producing initial measurements of a first reference location and a second reference location, wherein the first reference location and the second reference location are designed to produce different measurement results; producing subsequent measurements of the first reference location and the second reference location; and using the initial measurements of the first reference location and the second reference location and the subsequent measurements of the first reference location and the second reference location to determine the calibration error of the ellipsometer whichs structurally arranged and functionally operated as claimed in claims 1,8,15.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Tu T. Nguyen whose telephone number is (571) 272-2424. The examiner can normally be reached on T-F 7:30-5:30.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Gregory Toatley Jr. can be reached on (571) 272-2800 Ext. 77. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Tu T. Nguyen Primary Examiner Art Unit 2877

08/10/2005